

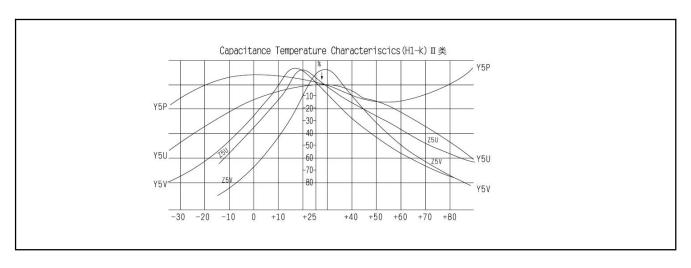
\square Appearance Size and Structure

| Part No | Model | L Min(mm) | D Max(mm) | T Max(mm) | F (mm) | d (mm) | Appearance Size |
|------------|-------------|--------------|--------------|--------------|--------------------|----------------|--------------------|
| 1 | Y2-Y5V-471M | 25 | 8. 0 | 4. 0 | 7. 5 <u>+</u> 0. 5 | 0.6 ± 0.05 | → D → → ←T |
| 2 | Y2-Y5V-152M | 25 | 8. 0 | 4. 5 | 7. 5 <u>+</u> 0. 5 | 0.6 ± 0.05 | |
| 3 | Y2-Y5V-472M | 25 | 10 | 4. 5 | 7. 5 <u>+</u> 0. 5 | 0.6 ± 0.05 | - b + d |
| 4 | Y2-Y5V-222M | 25 | 8. 0 | 4. 0 | 7. 5 <u>+</u> 0. 5 | 0.6 ± 0.05 | |
| 5 | Y2-Y5V-332M | 25 | 9. 0 | 4. 5 | 7. 5 <u>+</u> 0. 5 | 0.6 ± 0.05 | |

□ Temperature Coeficient

| Code | T. R. | Cap change | | |
|------|-----------|-------------|--|--|
| Y5V | -25℃~+85℃ | +22%~ — 82% | | |
| | | | | |

□ Capacitance and Temperature Curve





☐ According to:Specification

| GB/T 2693 | 《Fixed capacitors for use in electronic equipment | | | |
|------------|---|--|--|--|
| | Part1: Generic specification | | | |
| GB/T 5966 | «Fixed capacitors for use in electronic equipment | | | |
| | Part8: Sectional specification | | | |
| | Fixed capacitors of ceramic dielectric, Class I » | | | |
| GB/T 5968 | 《Fixed capacitors for use in electronic equipment | | | |
| | Part8: Sectional specification | | | |
| | Fixed capacitors of ceramic dielectric, Class II » | | | |
| GB 11305 | 《Fixed capacitors for use in electronic equipment | | | |
| | Sectional specification | | | |
| | Fixed capacitors of ceramic dielectric, Class III》 | | | |
| GB/T 14472 | 《Fixed capacitors for use in electronic equipment | | | |
| | Part14: Sectional specification | | | |
| | Fixed capacitors for electromagnetic interference suppression and | | | |
| | connection to the supply mains» | | | |
| GB2828 | 《Sampling procedures and tables for lot-by-lot inspection byattributes》 | | | |
| GB2829 | 《Sampling procedures and tables for periodic inspection byattributes》 | | | |

Quality Assurance(OQC) and Test

| Check item | Check level | | |
|----------------------------|-------------|-------|--|
| (lot) | IL | AQL | |
| 1. Appearance | S4 | 2. 5 | |
| 2. Size | 0 1 | 2. 0 | |
| 1. Capacitance | | | |
| 2. DF | | | |
| 3. Voltage proof | II | 0. 25 | |
| 4. Insulation resistance | | | |
| 1. Solder ability of leads | S3 | 2. 5 | |



$\hfill\Box$ Specification and Testing Method

| Item | Specification | Testing Method | |
|--|---------------|---|--|
| 1. Operating Temperature Range | -25~+85℃ | | |
| 2. Capacitance | M: +20%-20% | Temperature: $25\pm2^{\circ}$ C Voltage: 1.0 ± 0.2 Vrms Frequency: 1.0 ± 0.2 KHz | |
| 3. DF | 5.0%max | Temperature: $25\pm2^{\circ}$ C Voltage: 1.0 ± 0.2 Vrms Frequency: 1.0 ± 0.2 KHz | |
| 4. Insulation Resistance (IR) | 5000MΩmin | Apply voltage: 500VDC Apply current: I≤0.05A Test time: 1min | |
| 5. Dielectric Strength No failure | | Rated voltage: Y2: 1500VAC Apply current: $I \le 2\pi \times f \times C \times U$ Test time: 1min | |
| 6. Temperature Characteristic Y5V: +22%~ -82% | | The capacitance measurement shall be made at each step: Before Test: Set the capacitor for lhour at 85 ± 2 °C , after 24 ± 2 hour at room temperature, then can be measured. Step Temperature 1 20 ± 2 °C 2 -25 ± 3 °C 3 20 ± 2 °C 4 85 ± 2 °C 5 20 ± 2 °C | |



| Item | | Specification | Testing Method | |
|----------------------------|--|--|--|--|
| | Appearance | No marked defect | Apply rated voltage for 500 hours at 40±2°C in 90 to 95%RH | |
| | Capacitance change | Y5V: △C/C≤30% | Pre-treatment: capacitor shall be stored 1hour at $85\pm2^{\circ}$ C after at normal temperature for 24 ± 2 hour | |
| 10. Humidity | DF | Y5V: 7.5%max | before initial measurements. Post-treatment: capacitor shall be | |
| loading | | | measured after 24±2 hours at normal temperature. | |
| | Insulation Resistance (IR) | 3000MΩmin | | |
| | Appearance | No marked defect | Apply 150% of the rated voltage for 1000 hours at 85±2℃ | |
| | Capacitance change | Y5V: △C/C≤30% | Pre-treatment: capacitor shall be stored 1hour at $85\pm2^{\circ}$ after at normal temperature for 24 ± 2 hour before initial measurements. Post-treatment: capacitor shall be measured after 24 ± 2 hours at normal temperature. | |
| 11.Life Test | DF | Y5V: 7.5%max | | |
| | Insulation Resistance (IR) | 3000MΩmin | | |
| 12. Strength of | Dielectric strength | Lead wire shall not cut off, | As a figure fix the body of capacitor, apply a tensile weight gradually to each lead in the radial direction of capacitor up to 10N and keep it for 10±15 sec. | |
| lead | Bending | Capacitor shall not be broken. | Each lead wire shall be subjected to 5N weight and then $\pm 45^{\circ}$ bend twice. | |
| | Turn back strength | | Each lead wire shall be turn back twice at 180°. | |
| 13. Solderability of leads | Lead wire shall be over 95% of the cir | e soldered with coated recumferential direction. | The lead wire of a capacitor shall be dipped into flax and then into molten solder of $235\pm5^{\circ}$ °C for 2 ± 0.5 sec. | |